

80V N-Channel Power MOSFET

DESCRIPTION

The BLM04N08 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge. It can be used in a wide variety of applications.

Application

- Power switching application
- Hard switched and High frequency circuits
- Uninterruptible power supply

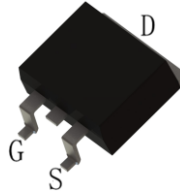
KEY CHARACTERISTICS

- $V_{DS} = 80V, I_D = 200A$
 $R_{DS(ON)} < 4m\Omega @ V_{GS}=10V$
- High density cell design for lower R_{dson}
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high EAS
- Excellent package for good heat dissipation

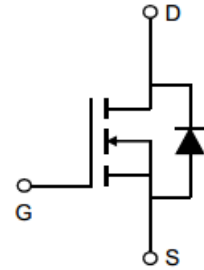
100% UIS TESTED!
100% DVDS TESTED!



TO-220 Top View



TO-263 Top View



Schematic diagram

Package Marking And Ordering Information

Device Marking	Ordering Codes	Package	Product Code	Packing
M04N08	BLM04N08-P	TO-220	BLM04N08	Tube
M04N08	BLM04N08-B	TO-263	BLM04N08	Reel

Absolute Maximum Ratings ($T_A=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	80	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	200	A
Drain Current-Pulsed ^(Note 1)	I_{DM}	800	A
Maximum Power Dissipation ($T_C=25^\circ C$)	P_D	270	W
Single pulse avalanche energy ^(Note 2)	E_{AS}	1600	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 175	$^\circ C$

Thermal Characteristic

Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.41	$^\circ C/W$
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Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	80	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=80V, V_{GS}=0V$	-	-	1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
On Characteristics						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2	3	4	V
Drain-Source On-State Resistance ^(Note 3)	$R_{DS(on)}$	$V_{GS}=10V, I_D=50A$	-	3.5	4	m Ω
Forward Transconductance	g_{FS}	$V_{DS}=5V, I_D=15A$	-	17	-	S
Dynamic Characteristics						
Input Capacitance	C_{iss}	$V_{DS}=25V, V_{GS}=0V,$ $f=1.0MHz$	-	13200	-	pF
Output Capacitance	C_{oss}		-	-950	-	pF
Reverse Transfer Capacitance	C_{rss}		-	810	-	pF
Switching Characteristics ^(Note 4)						
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=40V, I_D=40A,$ $V_{GS}=10V, R_{GEN}=3\Omega$	-	26	-	nS
Turn-on Rise Time	t_r		-	20	-	nS
Turn-Off Delay Time	$t_{d(off)}$		-	50	-	nS
Turn-Off Fall Time	t_f		-	18	-	nS
Total Gate Charge	Q_g	$V_{DS}=64V, I_D=80A$ $V_{GS}=10V$	-	257	-	nC
Gate-Source Charge	Q_{gs}		-	76	-	nC
Gate-Drain Charge	Q_{gd}		-	80	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_S=80A$	-	-	1.2	V

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. EAS condition : $T_j=25^\circ C, V_{DD}=50V, V_G=10V, L=0.5mH, R_g=1\Omega$
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production.

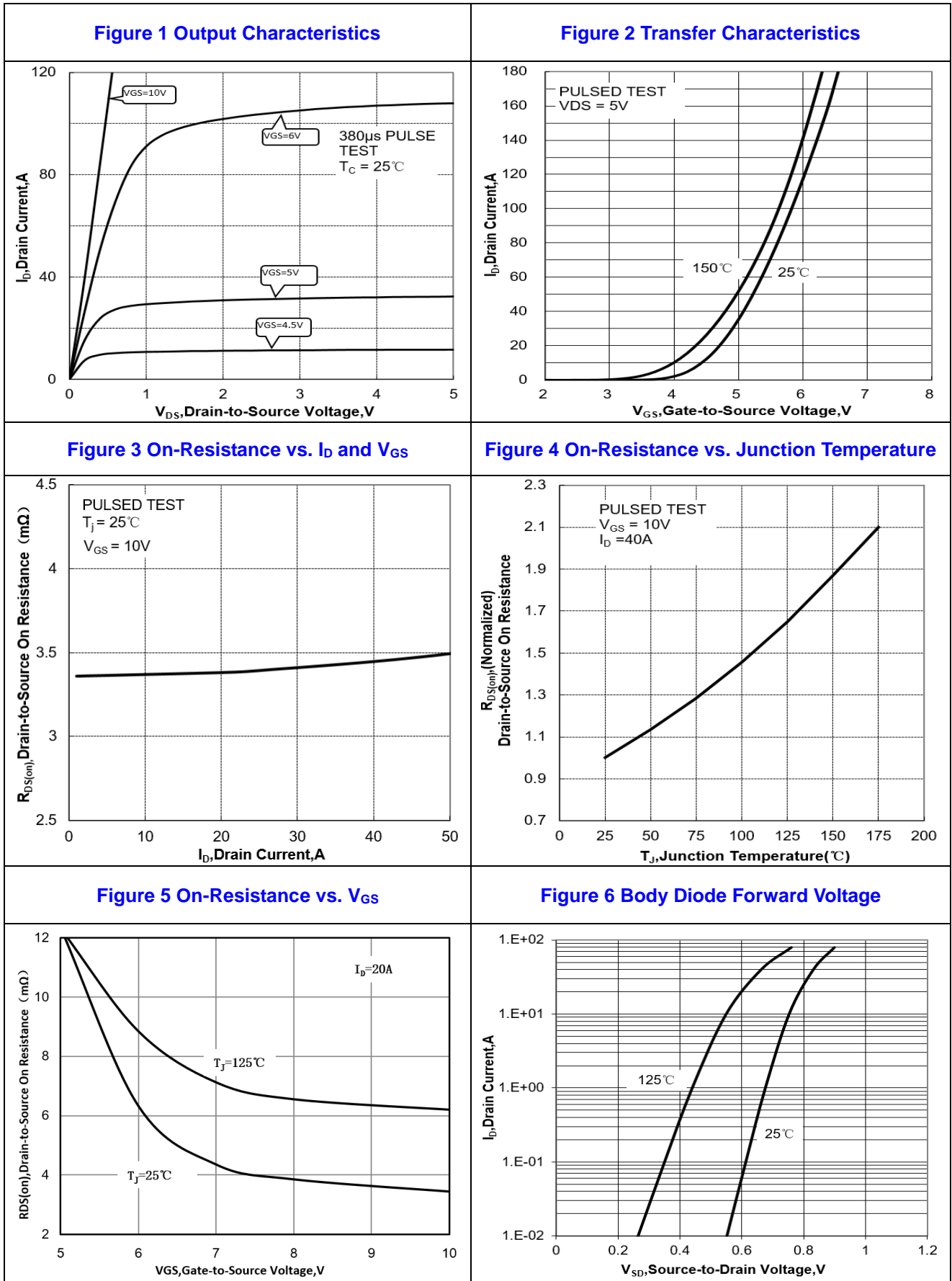
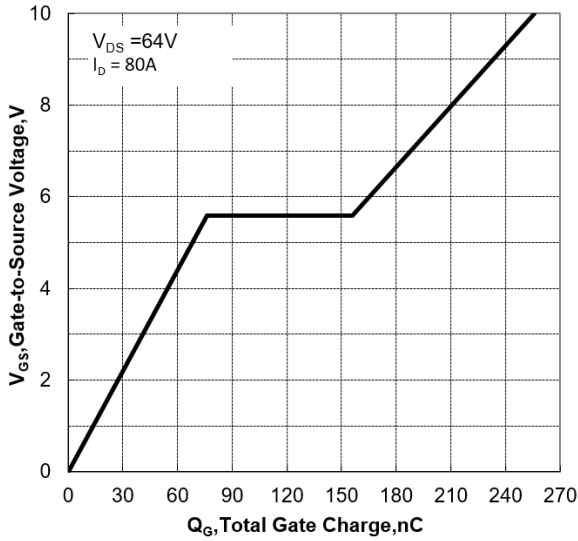
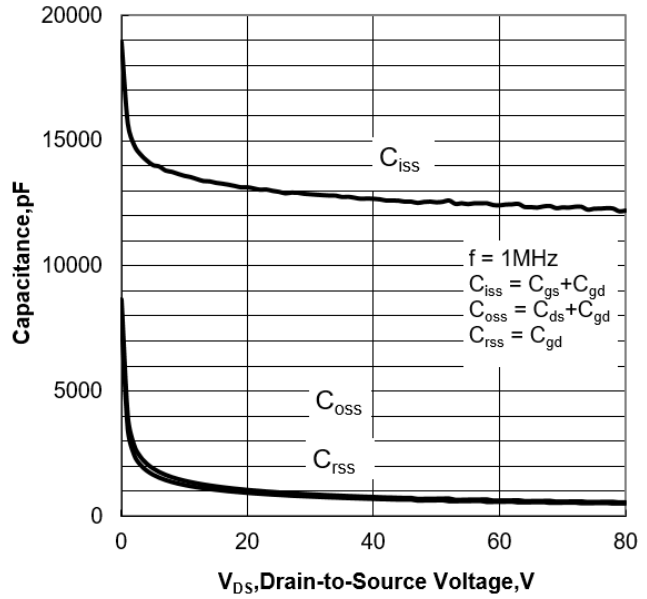
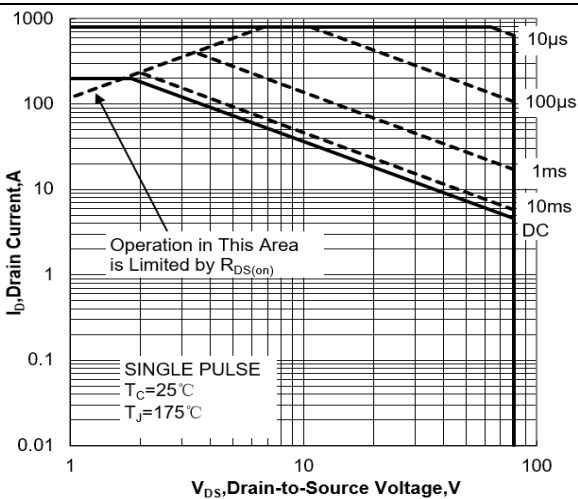
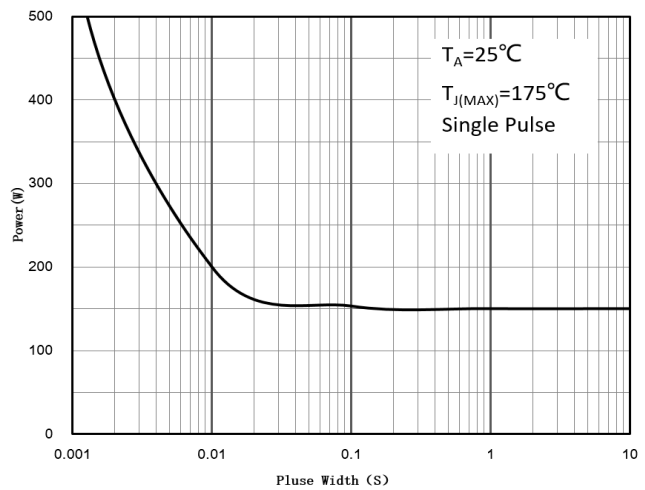
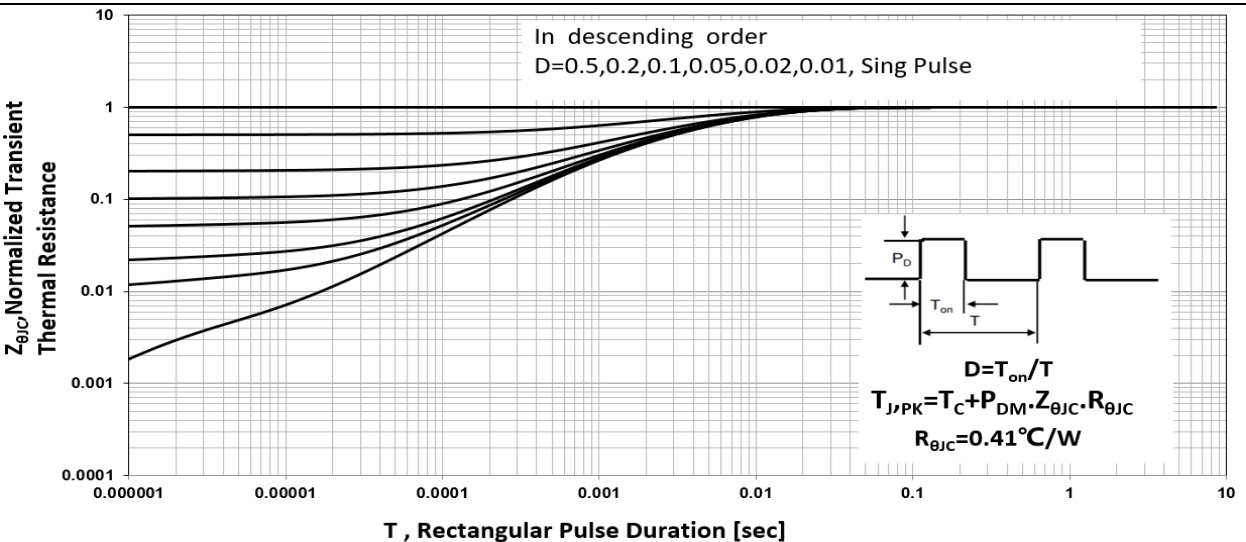
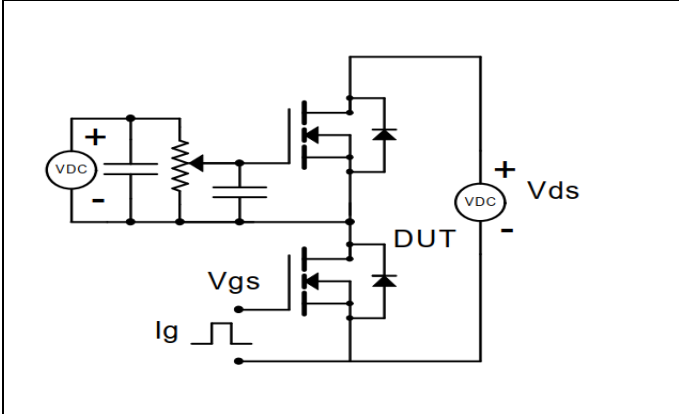
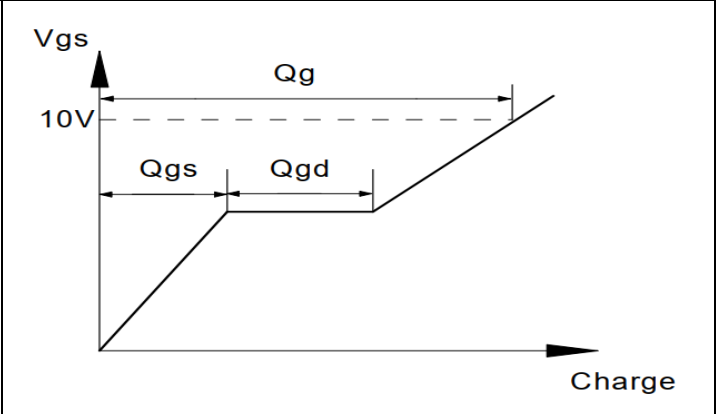
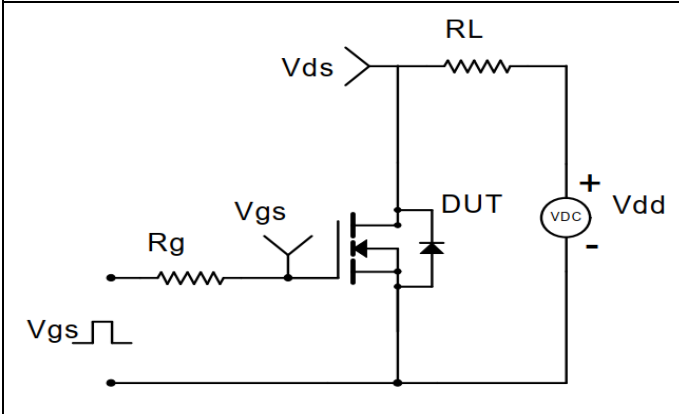
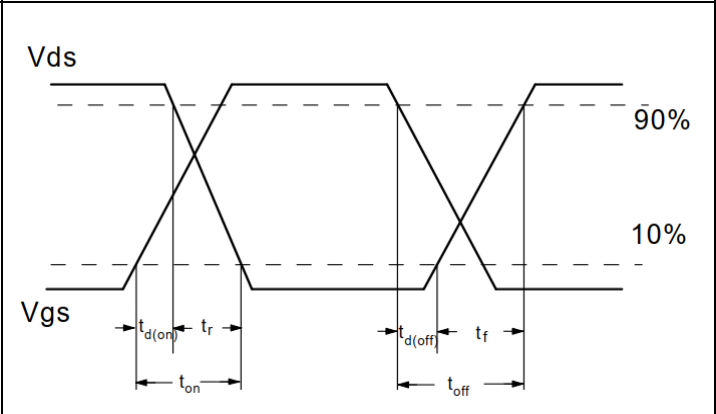
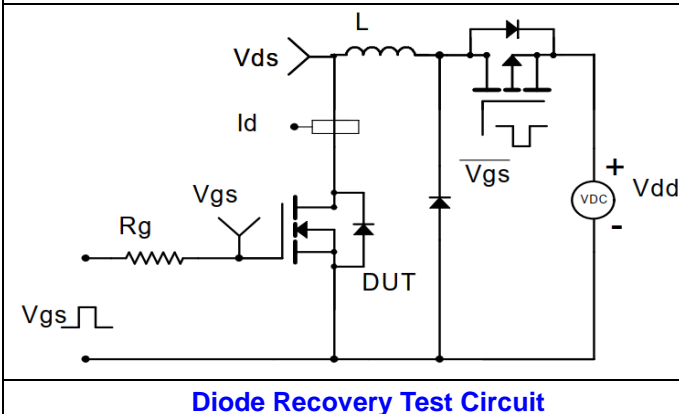
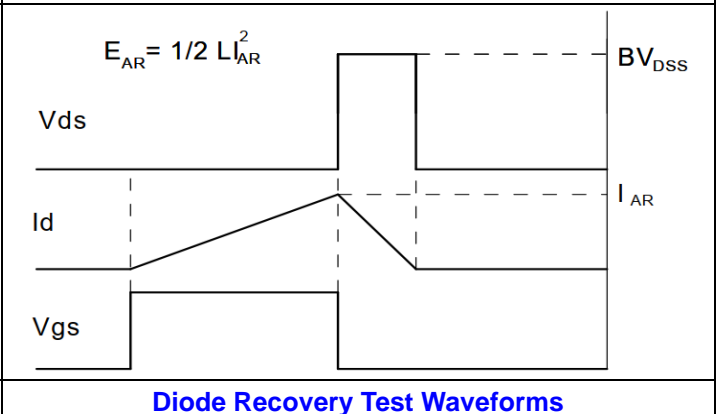
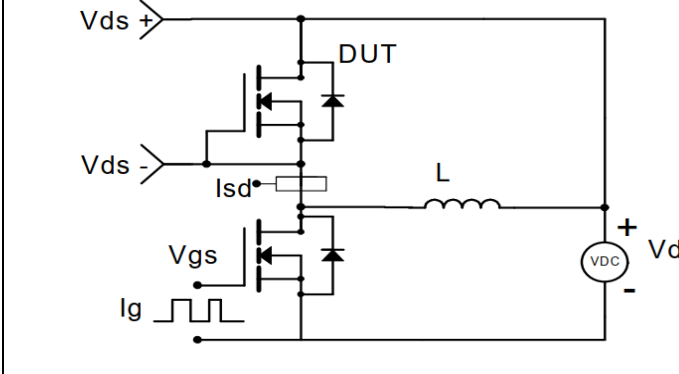
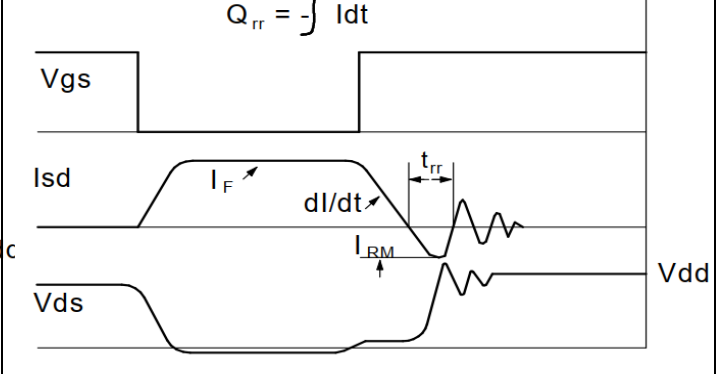
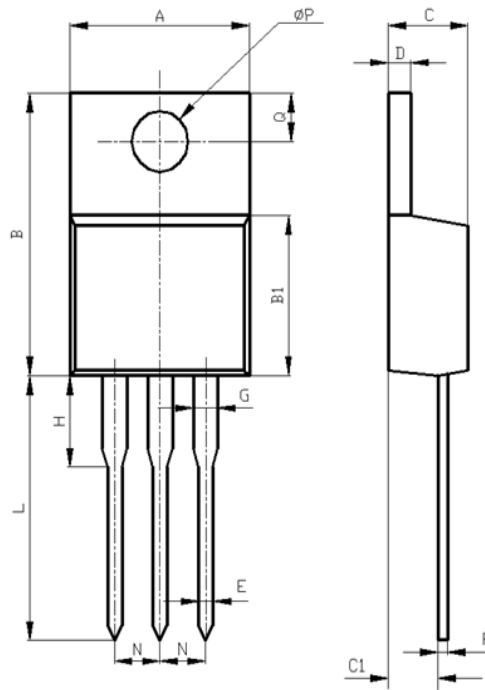
Characteristics Curves


Figure 7 Gate-Charge Characteristics

Figure 8 Capacitance Characteristics

Figure 9 Maximum Forward Biased Safe Operation Area

Figure 10 Single Pulse Power Rating Junction-to-Ambient

Figure 11 Normalized Maximum Transient Thermal Impedance


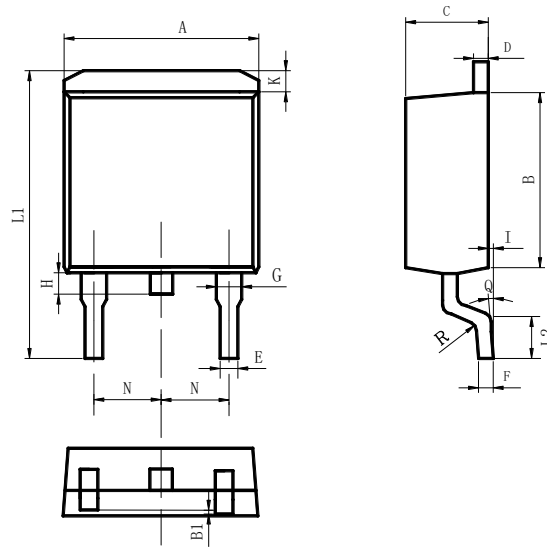
Test Circuit and Waveform

Gate Charge Test Circuit	Gate Charge Test Waveform
 <p>The diagram shows a MOSFET (DUT) in a common-emitter configuration. The gate is driven by a pulse source I_g through a resistor. The drain is connected to a load resistor and a DC source V_{DC}. The source is grounded.</p>	 <p>The graph plots gate voltage V_{gs} against charge. It shows a linear ramp up to a plateau at 10V, followed by a linear ramp down. The total area under the curve is labeled Q_g. The area under the rising ramp is Q_{gs} and the area under the falling ramp is Q_{gd}.</p>
Resistive Switching Test Circuit	Resistive Switching Test Waveforms
 <p>The diagram shows a MOSFET (DUT) in a common-emitter configuration. The gate is driven by a pulse source V_{gs} through a resistor R_g. The drain is connected to a load resistor R_L and a DC source V_{DD}. The source is grounded.</p>	 <p>The graph shows the drain-source voltage V_{ds} and gate voltage V_{gs} waveforms. V_{gs} is a square wave. V_{ds} shows a trapezoidal shape during switching. Key parameters are labeled: $t_{d(on)}$, t_r, t_{on}, $t_{d(off)}$, t_f, and t_{off}. The voltage levels are marked at 90% and 10%.</p>
Unclamped Inductive Switching (UIS) Test Circuit	Unclamped Inductive Switching (UIS) Test Waveforms
 <p>The diagram shows a MOSFET (DUT) in a common-emitter configuration. The gate is driven by a pulse source V_{gs} through a resistor R_g. The drain is connected to an inductor L and a diode. The source is grounded. A DC source V_{DD} is connected to the drain.</p>	 <p>The graph shows the drain-source voltage V_{ds}, drain current I_d, and gate voltage V_{gs} waveforms. V_{gs} is a square wave. I_d shows a linear ramp up and down. V_{ds} shows a trapezoidal shape during switching. The energy stored in the inductor is given by $E_{AR} = 1/2 L I_{AR}^2$. The peak voltage is BV_{DSS} and the peak current is I_{AR}.</p>
Diode Recovery Test Circuit	Diode Recovery Test Waveforms
 <p>The diagram shows a MOSFET (DUT) in a common-emitter configuration. The gate is driven by a pulse source I_g through a resistor. The drain is connected to a load resistor L and a diode. The source is grounded. A DC source V_{DC} is connected to the drain.</p>	 <p>The graph shows the drain-source voltage V_{ds}, drain current I_{sd}, and gate voltage V_{gs} waveforms. V_{gs} is a square wave. I_{sd} shows a trapezoidal shape during switching. V_{ds} shows a trapezoidal shape during switching. The reverse recovery time t_{rr} is indicated. The peak current is I_F and the peak reverse current is I_{RM}. The energy stored in the inductor is given by $Q_{rr} = \int I_{sd} dt$.</p>

Package Description


Items	Values(mm)	
	MIN	MAX
A	9.60	10.6
B	15.0	16.0
B1	8.90	9.50
C	4.30	4.80
C1	2.30	3.10
D	1.20	1.40
E	0.70	0.90
F	0.30	0.60
G	1.17	1.37
H	2.70	3.80
L	12.6	14.8
N	2.34	2.74
Q	2.40	3.00
ϕP	3.50	3.90

TO-220 Package



Items	Values(mm)	
	MIN	MAX
A	9.80	10.40
B	8.90	9.50
B1	0	0.10
C	4.40	4.80
D	1.16	1.37
E	0.70	0.95
F	0.30	0.60
G	1.07	1.47
H	1.30	1.80
K	0.95	1.37
L1	14.50	16.50
L2	1.60	2.30
I	0	0.2
Q	0°	8°
R	0.4	
N	2.39	2.69

TO-263 Package

NOTE:

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shanghai Belling reserves the right to make changes in this specification sheet and is subject to change without prior notice.

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